



Power MOSFETS

DATASHEET

LM80025NAM8A

N-Channel
Enhancement Mode MOSFET

- Leadpower-semi CO., LTD.
- sales@leadpower-semi.com
- (03) 6577339 FAX : (03) 6577229
- www.leadpower-semi.com



Quality Management Systems
ISO 9001:2015 Certificate

N-Channel Enhancement Mode MOSFET

Pin Description

LFPACK56		Symbol	Symbol	N-Channel	Unit
Top view	Bottom view			V _{DSS}	V
				R _{DSON-Max}	mΩ
				I _D	A

Feature

- Fast switching speed
- Reliable and Rugged
- ROHS Compliant & Halogen-Free
- 100% UIS and Rg Tested
- Moisture Sensitivity Level MSL1

Product Summary

- DC-to-DC converters
- Switch mode power supply
- Brushless DC motor control

Ordering Information

Orderable Part Number	Package Type	Form	Shipping	Marking
LM80025NAM8A	LFPACK56	Tape & Reel	4000 / Tape & Reel	80025 <input type="checkbox"/> <input type="checkbox"/> <input type="checkbox"/> <input type="checkbox"/> <input type="checkbox"/> <input type="checkbox"/>

Note : = Lot Code

Absolute Maximum Ratings (T_J=25°C Unless Otherwise Noted)

Symbol	Parameter	N-Channel	Unit
V _{DSS}	Drain-Source Voltage	80	V
V _{GSS}	Gate-Source Voltage	±20	
T _J	Maximum Junction Temperature	175	°C
T _{STG}	Storage Temperature Range	-55 to 175	°C
I _S	Diode Continuous Forward Current	T _c =25°C 95	A
I _{SP}	Diode Pulse Current	T _c =25°C 400	A
I _{DM}	Pulse Drain Current Tested	T _c =25°C 524 ^①	A
I _D	Continuous Drain Current	T _c =25°C 210 T _c =100°C 148	A
P _D	Maximum Power Dissipation	T _c =25°C 188 T _c =100°C 94	W
I _D	Continuous Drain Current	T _A =25°C 31.7 T _A =70°C 26.5	A
P _D	Maximum Power Dissipation	T _A =25°C 4.3 T _A =70°C 3.0	W
I _{AS^②}	Avalanche Current, Single pulse	L=0.1mH 57 L=0.5mH 32	A
E _{AS^②}	Avalanche Energy, Single pulse	L=0.1mH 162 L=0.5mH 256	mJ

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Thermal Characteristics

Symbol	Parameter	Rating	Unit
R _{θJC}	Thermal Resistance-Junction to Case	Steady State	0.8 °C/W
R _{θJA^③}	Thermal Resistance-Junction to Ambient	Steady State	35 °C/W

Note ① : Max. current is limited by junction temperature

Note ② : UIS tested and pulse width are limited by maximum junction temperature 175°C

Note ③ : Surface Mounted on 1in² FR-4 board with 1oz

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N-Channel Electrical Characteristics ($T_J=25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Static Electrical Characteristics						
$\mathbf{BV_{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$, $I_{DS}=250\mu\text{A}$	80	-	-	V
$\mathbf{I_{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=64\text{V}$, $V_{GS}=0\text{V}$	-	-	1	μA
$\mathbf{V_{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_{DS}=250\mu\text{A}$	1.3	1.9	3	V
$\mathbf{I_{GSS}}$	Gate Leakage Current	$V_{GS}=\pm 20\text{V}$, $V_{DS}=0\text{V}$	-	-	± 100	nA
$\mathbf{R_{DS(ON)}}^{\circledast}$	Drain-Source On-state Resistance	$V_{GS}=10\text{V}$, $I_{DS}=40\text{A}$	-	1.8	2.2	mΩ
		$V_{GS}=4.5\text{V}$, $I_{DS}=20\text{A}$		2.8	3.9	
$\mathbf{g_{fs}}$	Forward Transconductance	$V_{DS}=5\text{V}$, $I_{DS}=10\text{A}$	-	41	-	S
Dynamic Characteristics ^⑤						
$\mathbf{R_G}$	Gate Resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}$, Freq.=1MHz	-	0.9	-	Ω
$\mathbf{C_{iss}}$	Input Capacitance	$V_{GS}=0\text{V}$, $V_{DS}=40\text{V}$, Freq.=1MHz	-	6148	-	pF
$\mathbf{C_{oss}}$	Output Capacitance		-	1716	-	
$\mathbf{C_{rss}}$	Reverse Transfer Capacitance		-	191	-	
$\mathbf{t_{d(ON)}}$	Turn-on Delay Time	$V_{GS}=10\text{V}, V_{DS}=40\text{V}$, $I_D=1\text{A}, R_{GEN}=1\Omega$	-	18	-	nS
$\mathbf{t_r}$	Turn-on Rise Time		-	11	-	
$\mathbf{t_{d(OFF)}}$	Turn-off Delay Time		-	61	-	
$\mathbf{t_f}$	Turn-off Fall Time		-	91	-	
$\mathbf{Q_g}$	Total Gate Charge	$V_{GS}=4.5\text{V}, V_{DS}=40\text{V}$, $I_D=20\text{A}$	-	54		
$\mathbf{Q_g}$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=40\text{V}$, $I_D=20\text{A}$	-	106	-	nC
$\mathbf{Q_{gs}}$	Gate-Source Charge		-	18	-	
$\mathbf{Q_{gd}}$	Gate-Drain Charge		-	22	-	
Source-Drain Characteristics						
$\mathbf{V_{SD}}^{\circledast}$	Diode Forward Voltage	$I_{SD}=10\text{A}, V_{GS}=0\text{V}$	-	0.75	1.1	V
$\mathbf{t_{rr}}$	Reverse Recovery Time	$I_F=10\text{A}, V_R=40\text{V}$	-	84	-	nS
$\mathbf{Q_{rr}}$	Reverse Recovery Charge	$dI_F/dt=100\text{A}/\mu\text{s}$	-	99	-	nC

Note ④ : Pulse test (pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$).

Note ⑤ : Guaranteed by design, not subject to production testing.

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N-Channel Typical Characteristics

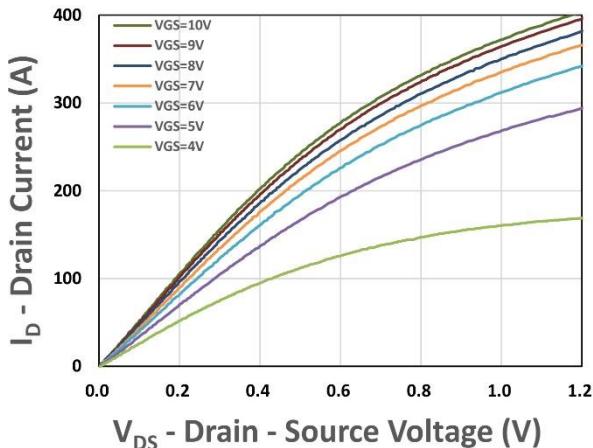


Figure 1. Output Characteristics

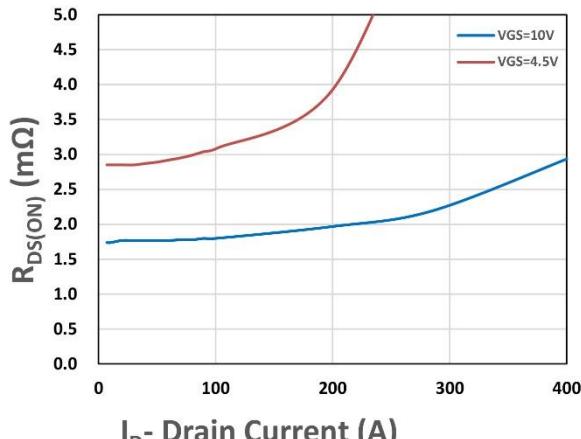


Figure 2. On-Resistance vs. ID

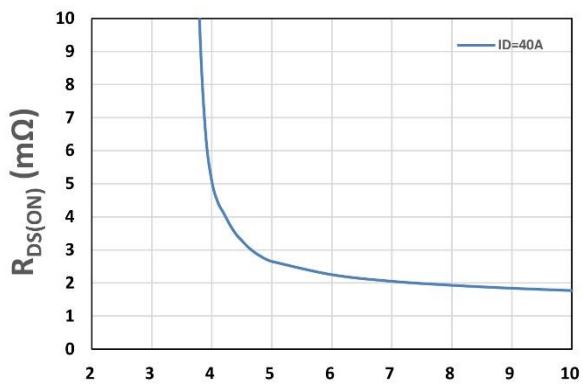


Figure 3. On-Resistance vs. VGS

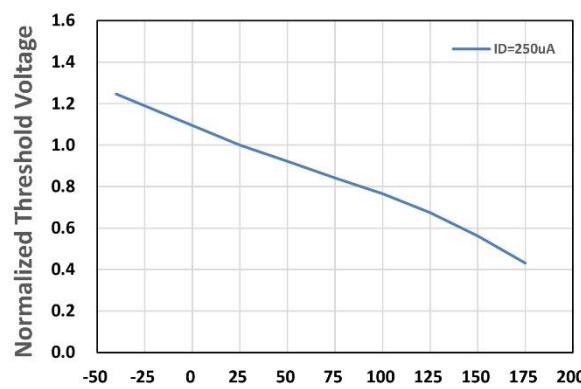


Figure 4. Gate Threshold Voltage

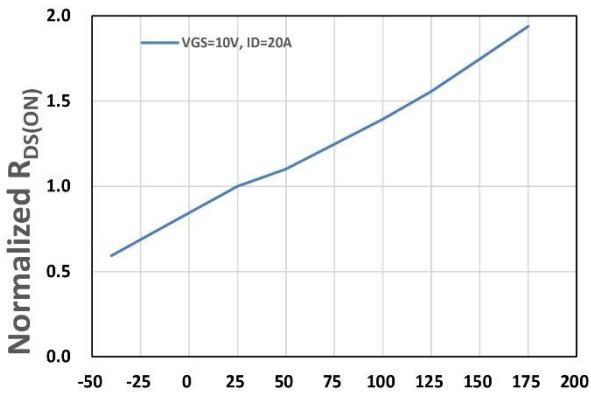


Figure 5. Drain-Source On Resistance

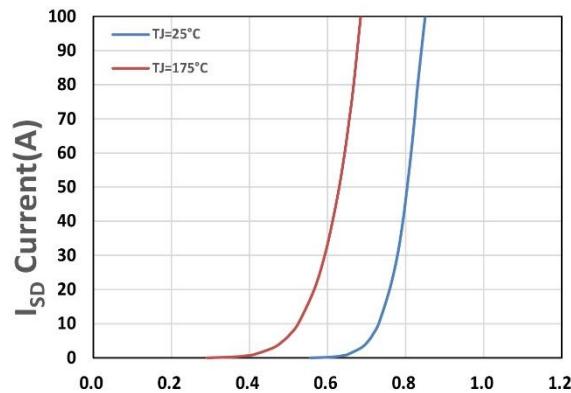
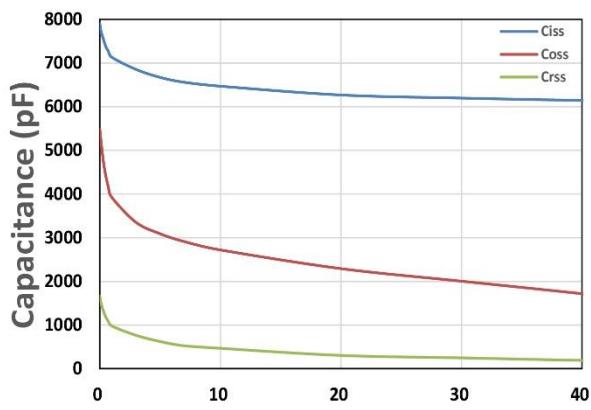


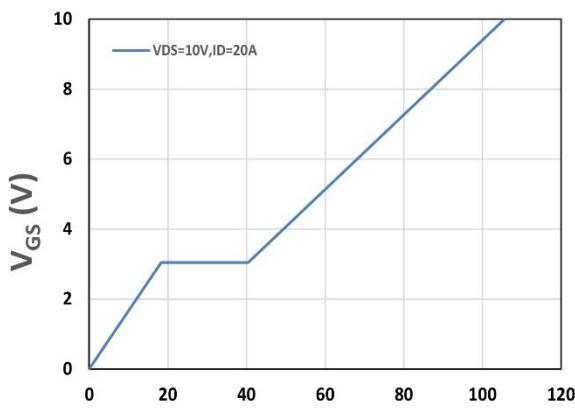
Figure 6. Source-Drain Diode Forward

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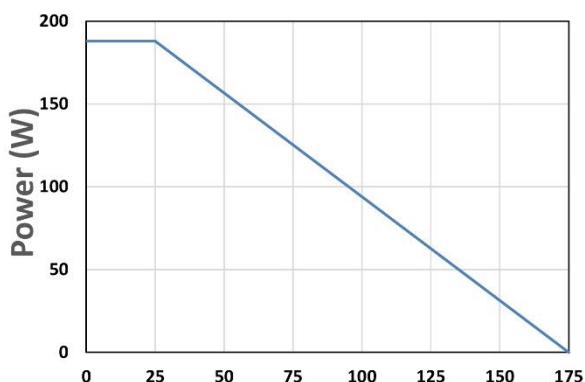
V_{DS} - Drain - Source Voltage (V)

Figure 7. Capacitance



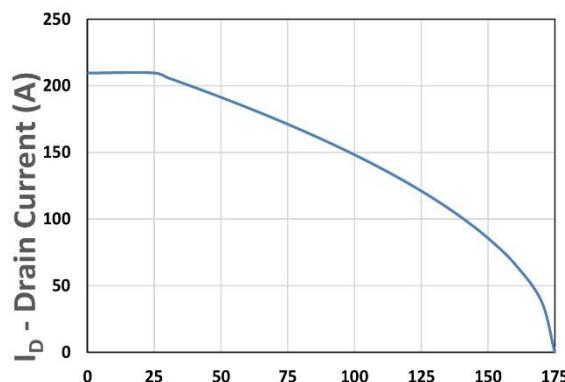
Q_g , Total Gate Charge (nC)

Figure 8. Gate Charge Characteristics



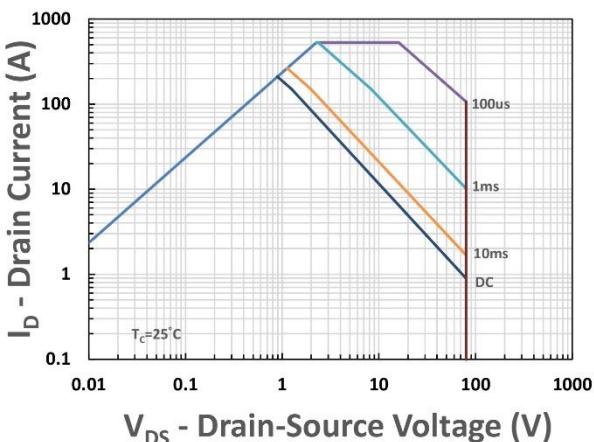
T_c -Case Temperature (°C)

Figure 9. Power Dissipation



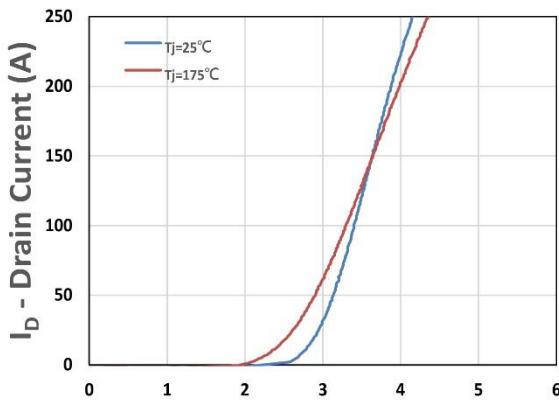
T_c -Case Temperature (°C)

Figure 10. Drain Current



V_{DS} - Drain-Source Voltage (V)

Figure 11. Safe Operating Area



V_{GS} - Gate - Source Voltage (V)

Figure 12. Transfer Characteristics

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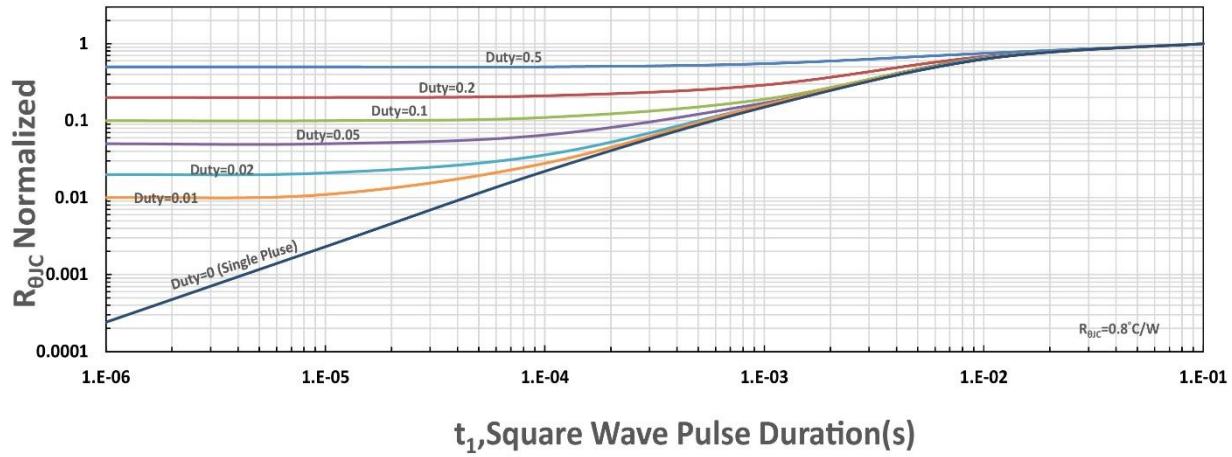


Figure 13. $R_{θJC}$ Transient Thermal Impedance